

Search Notes**Application/Control No.**

10/664,662

Examiner

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Applicant(s)/Patent under Reexamination

ISHIKAWA ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	423	2/8/2006	HN
	436		
	437		
	442		
	434		
	439		
	502		
	127.1		
	127.5		
Updated	search	10/6/2006	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	2/8/2006	HN
East; Text search (USPAT, US-PGPUB, JPO, EPO, DERWENT). See search history printout.	10/6/2006	HN